

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/568,358	ASPLAND, MARK	
		Examiner	Art Unit	Page 1 of 1
		JIANCHUN QIN	2837	

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0184992	12-2002	Brando, Marlon	84/411.00R
*	B	US-2,604,001	07-1952	GEORGE LEWAN	84/417
*	C	US-2002/0092406	07-2002	Hagiwara, Takashi	84/411.00R
*	D	US-4,026,185	05-1977	Migirian, George	84/411R
*	E	US-6,172,289	01-2001	Shelley, Thomas W.	84/411R
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	I					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.